

**WAFER ACCEPTANCE TESTING METHOD AND STRUCTURE OF A TEST KEY
USED IN THE METHOD**

Appl. No. : 10/707,398 Confirmation No. 1397
Applicant : Ping Hsu
Filed : December 10, 2003
TC/A.U. : 2829
Examiner : Pert, Evan T
Docket No. : NTCP0026USA0
Customer No. : 27765

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Commissioner for Patents
P.O. Box 1450
Alexandria VA 22313-1450

AMENDMENT

Sir:

- 5 In response to the Office action of November 17, 2004, please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 6 of this paper.

- 10 **Amendments to the Drawings** begin on page 9 of this paper and include both an attached replacement sheet and an annotated sheet showing changes.

Remarks/Arguments begin on page 10 of this paper.

An **Appendix** including amended drawing figures is attached following page 10 of this paper.